

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/026,610	QUIRK ET AL.	
Examiner	Art Unit	_
Jeffrey R. Snay	1743	

SEARCHED							
Class	Subclass	Date	Examiner				
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Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
prior search updated	6/11/2005	JRS	